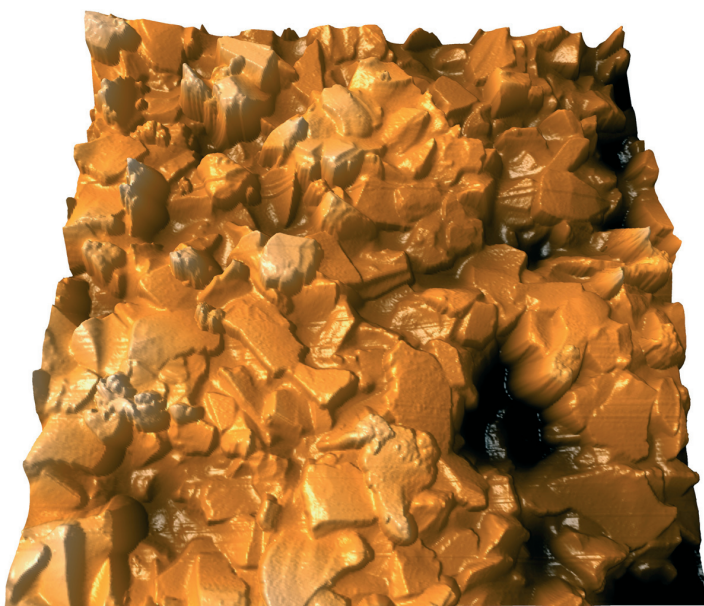


MFP-3D™ Extended Head for High Feature Samples

As sample features increase in height, a larger Z-range is required. Asylum Research has developed the MFP-3D Extended Head for use in its MFP-3D Atomic Force Microscopy (AFM) Systems. The new head design allows a scan range of 40µm in Z for samples with higher features, and in particular, for bioscience applications including living cells and plant imaging.



The 40µm Z scan range Extended Head is ideal for imaging bioscience samples such as living cells, plant imaging, and pulling on long-chained molecules.



2500 grit sand paper, 90µm scan. This sample required 19µm of Z range.

The MFP-3D Extended Head utilizes the same Nanopositioning System (NPS™) sensors found in the standard head for unprecedented precision and accuracy. Z sensor noise is <0.3nm Adev in a 0.1Hz-1 kHz bandwidth (BW) and sensor non-linearity less than 0.2% (Adev/full travel) at full scan; Z height noise <0.06nm Adev, 0.1Hz-1kHz BW.

The MFP-3D Extended Head is offered as an option in MFP-3D system configurations.

MFP-3D and NPS are trademarks of Asylum Research.